

Polish adaptation of the Modern Language Aptitude Test – a report on a project in progress.

Krzysztof Wilk (Adam Mickiewicz University, Poznań)

The aim of this presentation is to provide a brief overview of a project undertaken in the School of English A. Mickiewicz University to adapt into Polish a test of foreign language aptitude, the so called MLAT (*Modern Language Aptitude Test*) designed and developed by Carroll and Sapon in 1959.

Despite the criticism leveled against MLAT, it has withstood the test of time as the most robust and theoretically accomplished operationalization of the classical model of the construct of foreign language aptitude. Over the years MLAT has become a kind of benchmark and the main reference in both, data and theory driven research of individual differences in FL/L2 acquisition/learning. To date, the test has been used in at least 150 research projects published in journals or monographies and is widely cited as the most frequent and reliable tool measuring FL aptitude. Since its publication the test has been adapted into languages other than English or has become the basis for similar tests constructed in France, Italy, Japan, Germany, Spain, Turkey, Thailand, Denmark, and Hungary. In the light of the above it comes as a surprise that no such tool with strong psychometric characteristics similar to the MLAT has been developed in Poland. The current project is an attempt to remedy the situation.

The presentation will begin with the discussion of the reasons behind the motive to adapt MLAT rather than to develop an entirely new test of the construct in question. It will then highlight the strategy adopted in the adaptation and the stages which were followed in the process. Those will include, among others, the piloting of the test, item analysis and initial validation of the tool. Finally, possible applications of the MLAT-PL for diagnostic, research and prognostic purposes will be suggested. The presentation will be accompanied by the samples of the test's tasks.